



Subject card

Subject name and code	Basics of Electronics and Metrology, PG_00058908						
Field of study	Informatics						
Date of commencement of studies	October 2026	Academic year of realisation of subject			2026/2027		
Education level	first-cycle studies	Subject group			Obligatory subject group in the field of study Subject group related to scientific research in the field of study		
Mode of study	Part-time studies	Mode of delivery			at the university		
Year of study	1	Language of instruction			Polish		
Semester of study	1	ECTS credits			7.0		
Learning profile	general academic profile	Assessment form			assessment		
Conducting unit	Metrology and Electronic Systems Department -> Faculty of Electronics Telecommunications and Informatics -> Faculties of Gdańsk University of Technology						
Name and surname of lecturer (lecturers)	Subject supervisor	dr inż. Sylwia Babicz-Kiewlicz					
	Teachers	dr inż. Sylwia Babicz-Kiewlicz dr hab. inż. Jacek Jakusz dr inż. Stanisław Galla					
Lesson types	Lesson type	Lecture	Tutorial	Laboratory	Project	Seminar	SUM
	Number of study hours	30.0	0.0	15.0	0.0	0.0	45
	E-learning hours included: 0.0						
Learning activity and number of study hours	Learning activity	Participation in didactic classes included in study plan	Participation in consultation hours		Self-study	SUM	
	Number of study hours	45	10.0		120.0	175	
Subject objectives	Acquirement of basic knowledge and skills in the field of electronics and metrology						
Learning outcomes	Course outcome	Subject outcome			Method of verification		
	[K6_U02] can perform tasks related to the field of study in an innovative way as well as solve complex and nontypical problems, applying knowledge of physics, in changing and not fully predictable conditions	Student examines the basic working circuits of the transistor. Measures the frequency characteristics of operational amplifiers. It measures basic electrical quantities: voltage, current, resistance, power and electricity.			[SU1] Assessment of task fulfilment		

Subject contents

Course content – lecture

Electronics:

1. Passive elements and independent sources in the DC, frequency and time domains
2. Ohm's and Kirchhoff's laws
3. Norton's theorem
4. Method of circuit currents and node voltages
5. Analysis of elementary circuits in the frequency domain
6. Electronic signals: types of signals and their time courses
7. Properties and Ebers-Moll model of bipolar transistor (BJT)
8. Static characteristics
9. DC and AC analysis of BJT amplifier
10. Properties and Shichman-Hodges model of unipolar transistor (MOS)
11. Static characteristics
12. DC and AC analysis of MOS amplifier
13. Elementary electronic circuits; operational amplifier, generator
14. Basic logical functors: Invert, Nand, Nor

Metrology:

1. Basic metrology concepts: measurement, transducer, device, measurement system
2. Digital oscilloscope: operating principle, triggering methods, applications
3. Oscilloscope measurement methods: phases, pulse parameters, X/Y characteristics of elements and systems
4. Digital methods of measuring time intervals, discretization error
5. Digital methods of measuring low and high frequencies
6. Digital phase measurements
7. Characteristics of digital voltage measurement methods

	<p>8. Integration A/C converters with double integration</p> <p>9. Measurements of alternating voltages: measured parameters, AC/DC converters of effective value (True RMS)</p> <p>10. Digital multimeters: resistance/voltage converters</p> <p>11. Digital methods of measuring impedance parameters R, L, C, Z </p>															
Prerequisites and co-requisites	It is obligatory to read the Health and Safety Rules and the Regulations of the Metrology Laboratory. Teachers determine the form of verification. Without familiarizing yourself with the Health and Safety Rules and the Laboratory Regulations, it is not possible to start classes in the metrology laboratory.															
Assessment methods and criteria	<table border="1"> <thead> <tr> <th data-bbox="450 586 794 618">Subject passing criteria</th> <th data-bbox="794 586 1139 618">Passing threshold</th> <th data-bbox="1139 586 1485 618">Percentage of the final grade</th> </tr> </thead> <tbody> <tr> <td data-bbox="450 618 794 678">Test wstępny + Praca na zajęciach + Sprawozdanie</td> <td data-bbox="794 618 1139 678">50.0%</td> <td data-bbox="1139 618 1485 678">25.0%</td> </tr> <tr> <td data-bbox="450 678 794 734">Kolokwium/Prace domowe w formie grywalizacji</td> <td data-bbox="794 678 1139 734">50.0%</td> <td data-bbox="1139 678 1485 734">25.0%</td> </tr> <tr> <td data-bbox="450 734 794 766">Kolokwium</td> <td data-bbox="794 734 1139 766">50.0%</td> <td data-bbox="1139 734 1485 766">25.0%</td> </tr> <tr> <td data-bbox="450 766 794 797">Sprawozdanie</td> <td data-bbox="794 766 1139 797">50.0%</td> <td data-bbox="1139 766 1485 797">25.0%</td> </tr> </tbody> </table>	Subject passing criteria	Passing threshold	Percentage of the final grade	Test wstępny + Praca na zajęciach + Sprawozdanie	50.0%	25.0%	Kolokwium/Prace domowe w formie grywalizacji	50.0%	25.0%	Kolokwium	50.0%	25.0%	Sprawozdanie	50.0%	25.0%
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Example issues/ example questions/ tasks being completed	Discuss the method of digitally converting voltage to a digital value. Present the principle of digital time and frequency measurements. Use of an oscilloscope to observe and measure parameters of periodic and non-periodic signals.															
Practical activities within the subject	Not applicable															